

FEB 14 2006

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. .... 10/050,334  
Filing Date ..... January 15, 2002  
Inventor ..... Vishnu K. Agarwal  
Assignee ..... Micron Technology, Inc.  
Group Art Unit ..... 2813  
Examiner ..... Tuan H. Nguyen  
Attorney's Docket No. .... MI22-1913  
Title: Capacitor Fabrication Methods and Capacitor Constructions and  
Enhanced Surface

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

References – See Attached Form PTO-1449

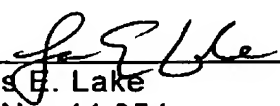
In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

Citation of these references is respectfully requested.

Respectfully submitted,

Dated: 14 Feb 2006

By: \_\_\_\_\_

  
James E. Lake  
Reg. No. 44,854

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-1913		SERIAL NO. 10/050,334	
<b>LIST OF ART CITED BY APPLICANT</b> (Use several sheets if necessary)					APPLICANT: Vishnu K. Agarwal			
					FILING DATE January 15, 2002		GROUP 2813	
<b>U.S. PATENT DOCUMENTS</b>								
*Examiner's Initials	AA	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
	AA	2005/0082593 A1	04/2005	Lee et al.				
	AB	2003/0215960	11/2003	Mitsubishi				
	AC	6,824,816	11/2004	Aaltonen et al.				
	AD	6,307,730	10/2001	Yamanishi				
	AE	6,800,892	10/2004	Bhattacharyya				
	AF							
	AG							
	AH							
	AI							
<b>FOREIGN PATENT DOCUMENTS</b>								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AJ							
	AK							
	AL							
<b>OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)</b>								
	AM							
	AN							
	AO							
<b>EXAMINER</b>		<b>DATE CONSIDERED</b>						
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								